

<div> <div>Notice of References Cited</div> </div>	<div>Application/Control No.</div> <div>10/612,193</div>	<div>Applicant(s)/Patent Under Reexamination</div> <div>TAKENAKA, TAKASHI</div>	
	<div>Examiner</div> <div>SAIF A. ALHIJA</div>	<div>Art Unit</div> <div>2128</div>	<div>Page 1 of 1</div>

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,611,947	08-2003	Higgins et al.	716/5
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	"On the Formal Verification of ATM Switches", Jianping Lu 1999.
*	V	"As good as gold", Blackett. IEEE 1996
*	W	"Applied Boolean Equivalence Verification and RTL Static Sign-Off", Harry Foster. IEEE 2001.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.